

Search Notes

Application/Control No.

10/706,288

Examiner

Nguyen T. Ha

Applicant(s)/Patent under
Reexamination

KURIHARA ET AL.

Art Unit

2831

SEARCHED

Class	Subclass	Date	Examiner
361	306.3	2/2/05	NH
	306.1		
	301.1		
	301.2		
	303		
	311		
	313		
	321.1		
	321.2		
	321.5		
257	532		
	295		
	296		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR